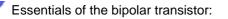
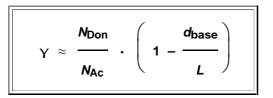
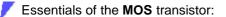
5.5.1 Summary: General Aspects of Silicon Technology



- High emitter doping (*N*_{Don} for npn transistor here) in comparison to base doping *N*_{Ac} for large current amplification factor γ = *I*_C/*I*_B.
- **N**Don/NAc $\approx \kappa$ = injection ratio.



- Small base width dbase (relative to diffusion length L) for large current amplification.
- Not as easy to make as the band-diagram suggests!



- Gate voltage enables Source-Drain current
- Essential process. Inversion of majority carrier type in channel below gate by:
 - Drive intrinsic majority carriers into bulk by gate voltage with same sign as majority carriers.
 - Reduced majority concentration *n*maj below gate increases minority carrier concentration *n*min via mass action law



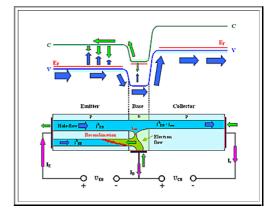
- An inversion channel with *n_{min} > n_{maj}* develops below the gate as soon as threshold voltage U_{Th} is reached.
- Current now can flow because the reversely biased pnjunction between either source or drain and the region below the gate has disappeared.

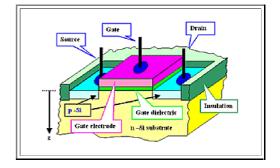
The decisive material is the gate dielectric (usually **SiO₂**). Basic requirement is:

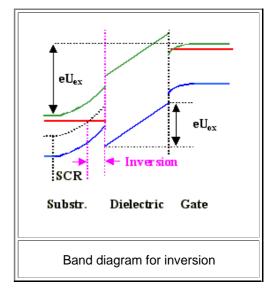
High capacity C_G of the gate electrode - gate dielectric - Si capacitor = high charge Q_G on electrodes = strong band bending = low threshold voltages U_G

It follows:

- Gate dielectric thickness *d*_{Di} ⇒ High breakdown field strength *U*_{Bd}
- Large dielectric constant ε_{r}
- No interface states.
- Good adhesion, easy to make / deposit, easy to structure, small leakage currents, ...







$Q_{\rm G} = C_{\rm G} \cdot U_{\rm G}$
Example: <i>U</i> = 5 V, <i>d</i> _{Di} = 5 nm ⇒ <i>E</i> = <i>U</i> / <i>d</i> _{Di} = 10 ⁷ V/cm ‼
∈ _r (SiO ₂) = 3.9

Integration means:

- Produce a large number (up to 1.000.000.000) of transistors (bipolar or MOS) and other electronic elements on a cm² of Si
- **2.** Keep thoses elements electrically insulated from each other.
- 3. Connect those elements in a meaningful way to produce a system / product.

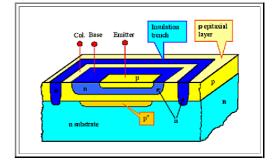
An integrated bipolar transistor does not resemble the textbook picture at all, but looks far more complicated \Rightarrow .

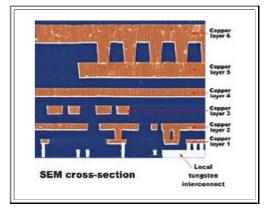
- This is due to the insulation requirements, the process requirements, and the need to interconnect as efficiently as possible.
- The epitaxial layer cuts down on the number of critical diffusions, makes insulation easier, and allows a "buried contact" structure.
- Connecting transistor / elements is complicated; it has to be done on several levels
 - Materials used are **AI** ("old"), **Cu** ("new"), **W**, (highly doped) poly-**Si** as well as various silicides.
 - Essential properties are the conductivity σ of the conductor, the dielectric constant $\epsilon_{\mathbf{r}}$ of the intermetal dielectric, and the resulting time constant $\tau = \sigma \cdot \epsilon_{\mathbf{r}}$ that defines the maximum signal transmision frequency through the conducting line.

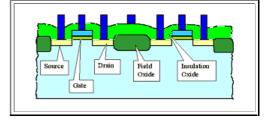
Integrating **MOS** transistors requires special measures for insulation (e.g. a field oxide) and for gate oxide production

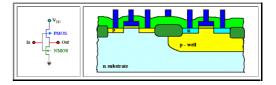
- Since a MOS transistor contains intrinsically a capacitor (the gate "stack"), the technology can be used to produce capacitors, too.
- CMOS allows to reduce power consumption dramatically.
 - The process, however, is more complex: Wells with different doping type need to be made.
- Using the third dimension (depth / height) might become necessary for integrating "large" structures into a small projected are (example: trench capacitor in **DRAMs** ⇒).
 - Unwanted "topology", however, makes integration more difficult.
 - Planarized technologies are a must since about 1995! ⇒

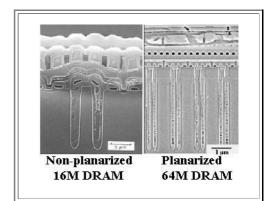
It ain't easy!

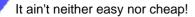




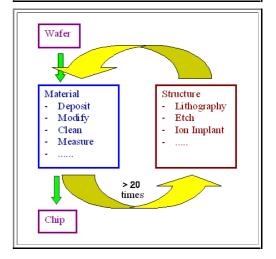


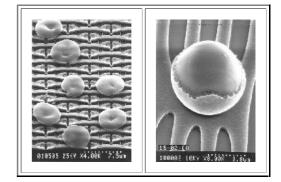






Property	Number
Feature size	0,2 µm
No. metallization levels	4 - 7
No. components	> 6 · 10 ⁸ (Memory)
Complexity	> 500 Process steps
Cost (development and 1 factory)	ca. \$ 6 · 10 ⁹





- Typical wafer size for new factories (2007) : 300 mm diameter, 775 μ m thickness, flatness in lower μ m region
 - Chip size a few cm², much smaller if possible
 - Yield Y = most important parameter in chip production = % of chips on a wafer that function (= can be sold).
 - Y = 29 % is a good value for starting production

Chip making = running about **20** times (roughly!!) through "materials" - "structuring" loop.

- About 400 600 individual processing steps (= in / out of special "machine") before chip is finished on wafer
- More than **30** processing steps for packaging (after separation of chips by cutting)
- Simple estimate: 99.9% perfection for each processing step means Y < 70 %.</p>
- Dirt in any form as "particles" on the surface of wafer, or as "contamination" inside the wafer is almost always deadly
 - Particles with sized not much smaller than minimum feature sizes (i.e. < 10 nm in 2007) will invariably cover structures and lead to local dysfunction of a transistor or whatever.
 - Point defects like metal atoms in the Si lattice may precipitate and cause local short circuits etc. from the "inside", killing transistors
 - One dysfunctional transistor out of 1.000.000.000 or so is enough to kill a chip!

Being extremely clean is absolutely mandatory for high Yields Y

- Use cleanrooms and hyper-clean materials!
- It won't be cheap!

Moore's law predicts exponentially growth of "chip complexity" with a high growth rate - how far will it reach?

- Problems and costs are growing exponentially with every new generation.
- It follows: The market must grow exponentially too, if you want to make a profit.
 - It follows: Large amounts of money can be easily made or lost.

Falling behind thecompetition in your technology and yields means certain death for companies without a monopoly in some product.



